

# New Service - Probe Card Report

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# New Service - Probe Card Report



## • Objective

- To provide automated monthly status report to customers that have regular wafer testing activities in SSMC or SSMC's sub-cons

## • Benefits to customer

- Keep track of number of probe card consigned to fab/sub-cons. For capacity planning, this information is crucial in deciding if additional probe card is required or re-location of probe card to another test house.
- Updated probe card condition(good/bad) information. Is spider need to be re-build? Is the latest low yield is caused by poor condition probe card?
- General information such as ownership & product name, & basic specification.
- \*Provide intelligent information that estimate the remaining life span of probe card in term of touchdown, number of wafers, & even days before next P&A or spider change.
- \*Provide unique probing performance indicator to each card.
- \*Provide comparison of recent lot yields, probing performance, touchdown if there are more than 1 card.

\*Information available for SSMC sorted products only.

# New Service - Probe Card Report



## Probe Card Report

**TX007XX**  
DotCom Technologies

\* Probe card information may differ depending on availability of data.

CARD 1
CARD 2
CARD 3

**Probe Card Rating**

10

Good

Customer Engineer: Ernest Wong  
Test Engineer: Ten, Berg, Oles

Tip Length List

**Probe Card Comparison**

Next 4 Lots: Year

Card 1	
Card 2	
Card 3	
Card 4	

**Probe Performance**

Card 1	
Card 2	
Card 3	

Touch Down Used % Broken Head P&A

Card 1	
Card 2	
Card 3	

Touch Down Used % Broken Head Splice Change

Card 1	
Card 2	
Card 3	

General	
Customer	DotCom Technologies
Card Product Name	TX007XX
SSMC Product Name	TMR007
Card Owned by	SSMC
Tester Platform	Verigy 93000 C400
Probe Type	TSK UP200
Loadboard ID	Verigy Genesic
Probe Tower ID	Verigy Genesic
Performance	
Recent Lots Yield	70.0%
Probing Performance	10.0 out of 10
Card Condition	Good
Intelligence	
Current Tip Length	152 um
Current Tip Diameter	12.4-19.8 um
Touch Down(TD)	11027
Cumulative TD	674218
Life Time TD	674218
Spider Change(SC)	0
TD LWH Next P&A	88973
TD LWH Next SC	719556
Wafer Lot Next P&A	445
Wafer Lot Next SC	3598
Days UWB Next P&A	4
Days UWB Next SC	35
Specification	
Probe Card Type	Cardlevel
PCB Part ID	T-293CR12-4.8
PCB Vendor	TCL
Probe Vendor	TCL
Probe City	TSL
Probe Material	RuW
Tip Length	200 +/- 20 um
Tip Diameter	15 +/- 5 um
Overdrive	Analyser 300/Prober 50 um
Board Depth	5.00 +/- 0.2 mm
Pad Size	x:75x65 y:65x75 um
Chip Size	x:3401 y:3481 um
Test Temperature	Room Temp - 85 degC